

# MOSFET – Dual, N-Channel, POWERTRENCH®

## 30 V, 22 m $\Omega$ and 10 m $\Omega$

## **FDMC7200S**

#### **General Description**

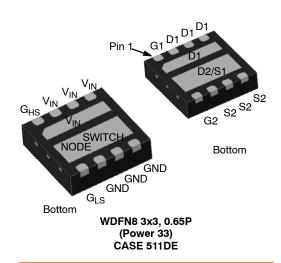
This device includes two specialized N-Channel MOSFETs in a dual Power 33 (3 mm x 3 mm MLP) package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous MOSFET (Q2) have been designed to provide optimal power efficiency.

#### **Features**

- Q1: N-Channel
  - Max  $R_{DS(on)} = 22 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 6 \text{ A}$
  - Max  $R_{DS(on)} = 34 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 5 \text{ A}$
- Q2: N-Channel
  - Max  $R_{DS(on)} = 10 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 8.5 \text{ A}$
  - Max  $R_{DS(on)} = 13.5 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 7.2 \text{ A}$
- This Device is Pb-Free, Halide Free and is RoHS Compliant

#### **Applications**

- Mobile Computing
- Mobile Internet Devices
- General Purpose Point of Load



#### **MARKING DIAGRAM**

ZXYKK FDMC 7200S

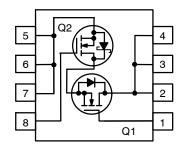
Z = Assembly Plant Code

XY = Date Code

KK = Lot Run Traceability Code

FDMC7200S = Device Code

#### PIN ASSIGNMENT



#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
FDMC7200S	WDFN8 (Pb-Free, Halide Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

#### **MOSFET MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ , unless otherwise noted)

Symbol	Parameter			Q1	Q2	Unit
$V_{DS}$	Drain to Source Voltage			30	30	V
V <sub>GS</sub>	Gate to Source Voltage		(Note 4)	±20	±20	V
$I_D$	Drain Current - Continuous (Package Limited)	T <sub>C</sub> = 25°C		18	13	Α
	<ul> <li>Continuous (Silicon Limited)</li> </ul>	T <sub>C</sub> = 25°C		23	46	
	- Continuous	T <sub>A</sub> = 25°C		7 (Note 1a)	13 (Note 1b)	
	- Pulsed			40	27	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	12	32	mJ
$P_D$	Power Dissipation for Single Operation	T <sub>A</sub> = 25°C		1.9 (Note 1a)	2.5 (Note 1b)	W
	Power Dissipation for Single Operation	T <sub>A</sub> = 25°C		0.7 (Note 1c)	1.0 (Note 1d)	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			–55 to	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## **THERMAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ , unless otherwise noted)

Symbol	Parameter	Q1	Q2	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	65 (Note 1a)	50 (Note 1b)	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient 180 (Note 1c) 125 (Note 1d)			
$R_{ heta JC}$	Thermal Resistance, Junction to Case	7.5	4.2	

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Unit	
OFF CHARACTERISTICS								
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D$ = 250 $\mu$ A, $V_{GS}$ = 0 $V$ $I_D$ = 1 mA, $V_{GS}$ = 0 $V$	Q1 Q2	30 30	_ _	- -	V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25°C $I_D$ = 1 mA, referenced to 25°C	Q1 Q2	- -	14 13	- -	mV/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V	Q1 Q2	- -	- -	1 500	μΑ	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q1 Q2	_ _	_ _	100 100	nA	
ON CHAR	ON CHARACTERISTICS							
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ = 250 $\mu$ A $V_{GS}$ = $V_{DS}$ , $I_D$ = 1 mA	Q1 Q2	1.0 1.0	2.3 2.0	3.0 3.0	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25°C $I_D$ = 1 mA, referenced to 25°C	Q1 Q2	- -	-5 -6	- -	mV/°C	
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6 A V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 5 A V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6 A, T <sub>J</sub> = 125°C	Q1	- - -	17 25 23	22 34 30	mΩ	
		$V_{GS} = 10 \text{ V, } I_D = 8.5 \text{ A} \\ V_{GS} = 4.5 \text{ V, } I_D = 7.2 \text{ A} \\ V_{GS} = 10 \text{ V, } I_D = 8.5 \text{ A, } T_J = 125^{\circ}\text{C}$	Q2	- -	7.8 10.3 11.4	10.0 13.5 13.1		
9FS	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_D = 6 \text{ A}$ $V_{DD} = 5 \text{ V}, I_D = 8.5 \text{ A}$	Q1 Q2	- -	29 43	<u>-</u> -	S	

**ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$  unless otherwise noted) (continued)

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Unit
DYNAMIC CHARACTERISTICS							
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz	Q1 Q2	_ _	495 1080	660 1436	pF
C <sub>oss</sub>	Output Capacitance		Q1 Q2	_ _	145 373	195 495	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		Q1 Q2	_ _	20 35	30 52	pF
$R_g$	Gate Resistance	f = 1 MHz	Q1 Q2	0.2 0.2	1.4 1.2	4.2 3.6	Ω
SWITCHIN	IG CHARACTERISTICS						
t <sub>d(on)</sub>	Turn-On Delay Time	Q1 V <sub>DD</sub> = 15 V, I <sub>D</sub> = 1 A,	Q1 Q2	_ _	11 7.6	20 15	ns
t <sub>r</sub>	Rise Time	$V_{GS} = 10 \text{ V}, \ \overline{R}_{GEN} = 6 \Omega$ Q2 $V_{DD} = 15 \text{ V}, \ I_D = 1 \text{ A},$	Q1 Q2	- -	3.1 1.8	10 10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	Q1 Q2	_ _	35 21	56 34	ns
t <sub>f</sub>	Fall Time		Q1 Q2	- -	1.3 8.5	10 17	ns
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0 \text{ V to } 10 \text{ V}$ Q1 $V_{DD} = 15 \text{ V}, I_D = 6 \text{ A}$ Q2 $V_{DD} = 15 \text{ V}, I_D = 8.5 \text{ A}$	Q1 Q2	-	7.3 15.7	10 22	nC
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ Q1 $V_{DD} = 15 \text{ V}, I_D = 6 \text{ A}$ Q2 $V_{DD} = 15 \text{ V}, I_D = 8.5 \text{ A}$	Q1 Q2	-	3.1 7.2	4.3 10	nC
$Q_{gs}$	Gate to Source Charge	Q1 V <sub>DD</sub> = 15 V, I <sub>D</sub> = 6 A	Q1 Q2	- -	1.8 3	- -	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	Q2 V <sub>DD</sub> = 15 V, I <sub>D</sub> = 8.5 A	Q1 Q2	- -	1 1.9	- -	nC
DRAIN-S	OURCE CHARACTERISTICS						
V <sub>SD</sub>	Source-Drain Diode Forward Voltage	$\begin{array}{c} V_{GS} = 0 \text{ V, } I_S = 6 \text{ A (Note 2)} \\ V_{GS} = 0 \text{ V, } I_S = 8.5 \text{ A (Note 2)} \\ V_{GS} = 0 \text{ V, } I_S = 1.3 \text{ A (Note 2)} \end{array}$	Q1 Q2 Q2	_ _	0.8 0.8 0.6	1.2 1.2 0.8	V
t <sub>rr</sub>	Reverse Recovery Time	Q1 I <sub>F</sub> = 6 A, di/dt = 100 A/μs	Q1 Q2	_ _	13 20	24 32	ns
Q <sub>rr</sub>	Reverse Recovery Charge	Q2 I <sub>F</sub> = 8.5 A, di/dt = 300 A/μs	Q1 Q2	_ _	2.3 15	10 24	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### NOTES:

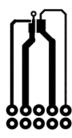
1.  $R_{\theta JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a. 65°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b. 50°C/W when mounted on a 1  $in^2$  pad of 2 oz copper



c. 180°C/W when mounted on a minimum pad of 2 oz copper



d. 125°C./W when mounted on a minimum pad of 2 oz copper

- Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.</li>
   Starting Q1: T = 25°C, L = 1 mH, I = 5 A, Vgs = 10 V, Vdd = 27V, 100% test at L = 3 mH, I = 4 A; Q2: T = 25C, L = 1 mH, I = 8 A, Vgs = 10 V, Vdd = 27 V, 100% test at L = 3 mH, I = 3.2 A.
- 4. As an N-ch device, the negative Vgs rating is for low duty cycle pulse ocurrence only. No continuous rating is implied.

#### TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) (T. I = 25°C, unless otherwise noted)

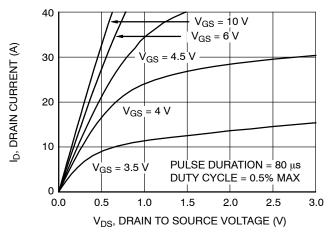


Figure 1. On Region Characteristics

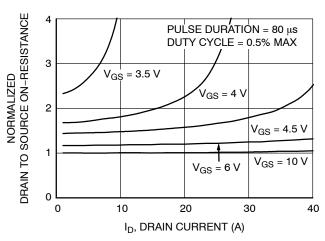


Figure 2. Normalized On–Resistance vs.

Drain Current and Gate Voltage

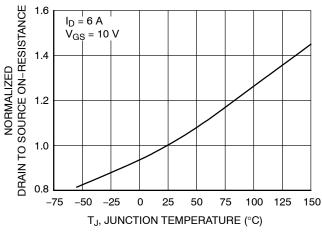


Figure 3. Normalized On Resistance vs. Junction Temperature

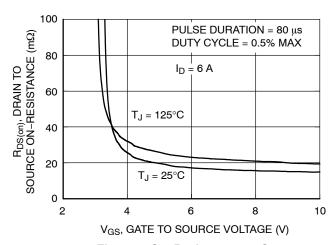


Figure 4. On-Resistance vs. Gate to Source Voltage

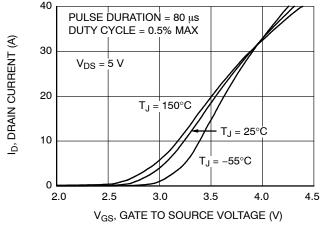


Figure 5. Transfer Characteristics

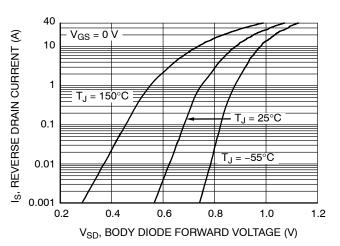


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

## TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) ( $T_J = 25$ °C, unless otherwise noted) (continued)

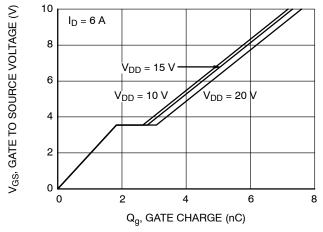


Figure 7. Gate Charge Characteristics

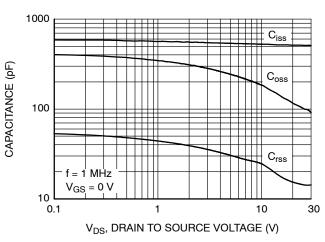


Figure 8. Capacitance vs. Drain to Source Voltage

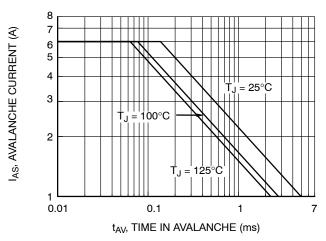


Figure 9. Unclamped Inductive Switching Capability

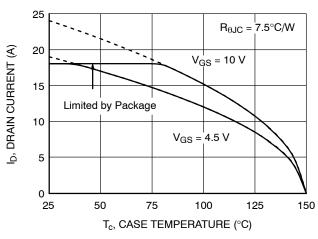


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

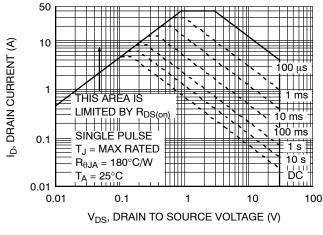


Figure 11. Forward Bias Safe Operating Area

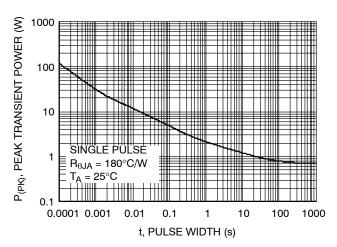


Figure 12. Single Pulse Maximum Power Dissipation

## TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) ( $T_J = 25$ °C, unless otherwise noted) (continued)

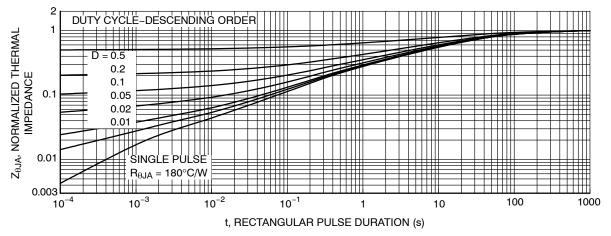


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

#### TYPICAL CHARACTERISTICS (Q2 N-CHANNEL) (T, = 25°C, unless otherwise noted)

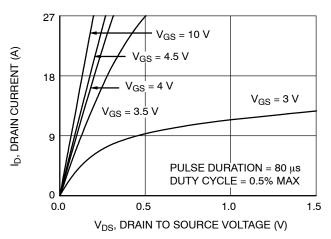


Figure 14. On-Region Characteristics

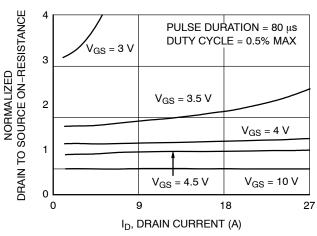


Figure 15. Normalized On–Resistance vs.
Drain Current and Gate Voltage

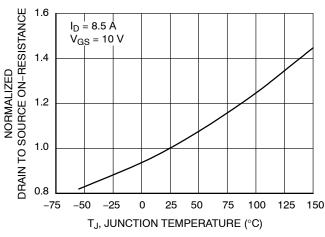


Figure 16. Normalized On Resistance vs.

Junction Temperature

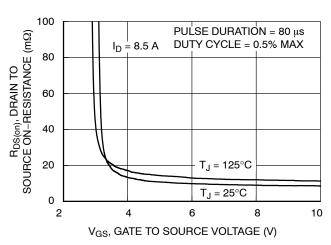
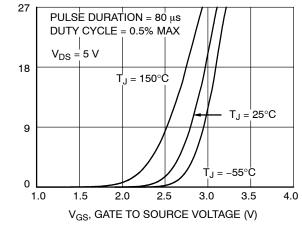


Figure 17. On-Resistance vs. Gate to Source Voltage



ID, DRAIN CURRENT (A)

Figure 18. Transfer Characteristics

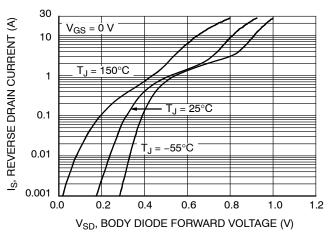


Figure 19. Source to Drain Diode Forward Voltage vs. Source Current

## TYPICAL CHARACTERISTICS (Q2 N-CHANNEL) (T<sub>J</sub> = 25°C, unless otherwise noted) (continued)

ID, DRAIN CURRENT (A)

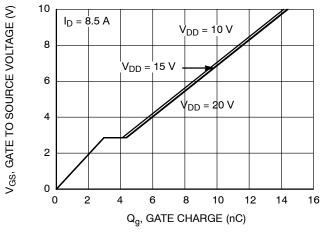


Figure 20. Gate Charge Characteristics

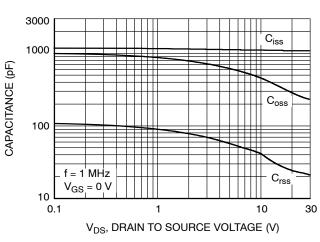


Figure 21. Capacitance vs. Drain to Source Voltage

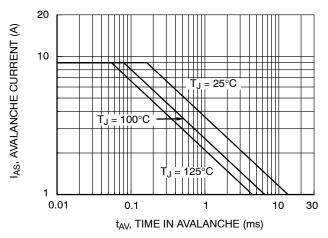


Figure 22. Unclamped Inductive Switching Capability

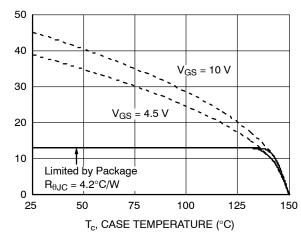


Figure 23. Maximum Continuous Drain Current vs. Case Temperature

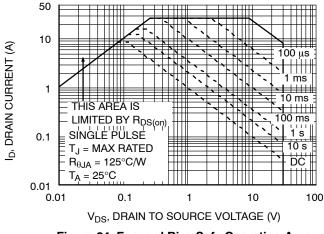


Figure 24. Forward Bias Safe Operating Area

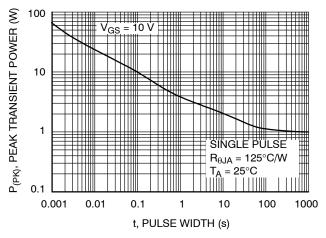


Figure 25. Single Pulse Maximum Power Dissipation

## TYPICAL CHARACTERISTICS (Q2 N-CHANNEL) ( $T_J = 25$ °C, unless otherwise noted) (continued)

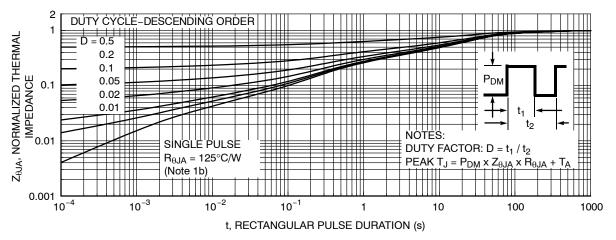


Figure 26. Junction-to-Ambient Transient Thermal Response Curve

#### TYPICAL CHARACTERISTICS (continued)

#### SyncFET™ Schottky Body Diode Characteristics

**onsemi**'s SyncFET process embeds a Schottky diode in parallel with POWERTRENCH MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 27 shows the reverse recovery characteristic of the FDMC7200S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

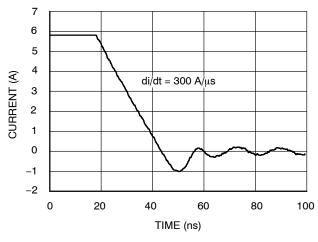


Figure 27. FDMC7200S SyncFET Body Diode Reverse Recovery Characteristic

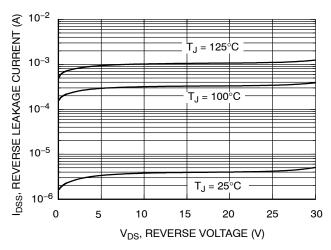


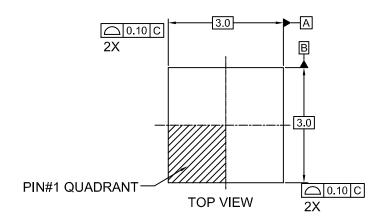
Figure 28. SyncFET Body Diode Reverse Leakage vs. Drain-Source Voltage

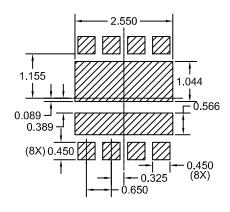
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WDFN8 3x3, 0.65P CASE 511DE ISSUE O

**DATE 31 AUG 2016** 

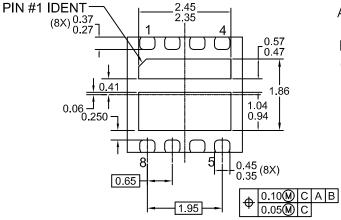




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## 

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  - B. DIMENSIONS ARE IN MILLIMETERS.
  - C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994



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